

# **Notice of References Cited**

Application/Control No.

10/074,141

Applicant(s)/Patent Under  
Reexamination  
BAJAJ ET AL.

Examiner

Edna Wong

*Edna Wong*

Art Unit

1753

Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,915,717	10-1975	Feldstein et al.	106/1.23
	B	US-1,919,000	07-1933	JOHN WERNLUND CHRISTIAN; et. al.	205/101
	C	US-1,841,978	01-1932	OPLINGER FLOYD F	205/301
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.